

#### FQPF6N80-VB Datasheet

# N-Channel 800V (D-S) Super Junction Power MOSFET

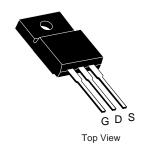
PRODUCT SUMMARY			
V <sub>DS</sub> (V) 800			
$R_{DS(on)}(\Omega)$	V <sub>GS</sub> = 10 V	1.2	
Q <sub>g</sub> (Max.) (nC)	200	)	
Q <sub>gs</sub> (nC)	24		
Q <sub>gd</sub> (nC)	110		
Configuration	Single		

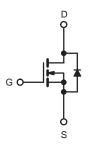
#### **FEATURES**

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Isolated Central Mounting Hole
- Fast Switching
- Ease of Paralleling
- Simple Drive Requirements
- Compliant to RoHS Directive 2002/95/EC









N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T <sub>C</sub>	= 25 °C, unl	ess otherwis	se noted)		
PARAMETER			SYMBOL	LIMIT	UNIT
Drain-Source Voltage			$V_{DS}$	800	V
Gate-Source Voltage			$V_{GS}$	± 30	v
Continuous Drain Current	V <sub>GS</sub> at 10 V	T <sub>C</sub> = 25 °C	I <sub>D</sub>	5	_
	GO	$T_C = 100 ^{\circ}C$		3.9	Α
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	21	
Linear Derating Factor				1.5	W/°C
Single Pulse Avalanche Energy <sup>b</sup>			E <sub>AS</sub>	770	mJ
Repetitive Avalanche Currenta			I <sub>AR</sub>	7.8	Α
Repetitive Avalanche Energy <sup>a</sup>			E <sub>AR</sub>	19	mJ
Maximum Power Dissipation	T <sub>C</sub> = 25 °C		P <sub>D</sub>	190	W
Peak Diode Recovery dV/dtc			dV/dt	2.0	V/ns
Operating Junction and Storage Temperature Rang	е		T <sub>J</sub> , T <sub>stg</sub>	- 55 to + 150	°C
Soldering Recommendations (Peak Temperature)	for	10 s		300 <sup>d</sup>	
Mounting Torque	6-32 or l	И3 screw		10	lbf ⋅ in
Mounting Torque	0-32 01 1	VIO SCIEW		1.1	N⋅m

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. V<sub>DD</sub> = 50 V, starting T<sub>J</sub> = 25 °C, L = 23 mH, R<sub>g</sub> = 25  $\Omega$ , I<sub>AS</sub> = 7.8 A (see fig. 12). c. I<sub>SD</sub>  $\leq$  7.8 A, dl/dt  $\leq$  140 A/ $\mu$ s, V<sub>DD</sub>  $\leq$  600 V, T<sub>J</sub>  $\leq$  150 °C.

<sup>\*</sup> Pb containing terminations are not RoHS compliant, exemptions may apply



THERMAL RESISTANCE RATI	ERMAL RESISTANCE RATINGS				
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-	40		
Case-to-Sink, Flat, Greased Surface	R <sub>thCS</sub>	0.24	-	°C/W	
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	-	0.65		

PARAMETER	SYMBOL	TES	T CONDITIONS	MIN.	TYP.	MAX.	UNIT
Static						,	
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub>	= 0 V, I <sub>D</sub> = 250 μA	800	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	e to 25 °C, I <sub>D</sub> = 1 mA	-	0.98	-	V/°C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> :	= V <sub>GS</sub> , I <sub>D</sub> = 250 μA	2.0	-	4.0	V
Gate-Source Leakage	I <sub>GSS</sub>		V <sub>GS</sub> = ± 20 V	-	-	± 100	nA
Zero Gate Voltage Drain Current	I <sub>DSS</sub>		= 800 V, V <sub>GS</sub> = 0 V V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C	-	-	100 500	μΑ
Drain-Source On-State Resistance	R <sub>DS(on)</sub>		$I_D = 3.7 \text{ A}^b$	-	1.2	-	Ω
Forward Transconductance	9fs		= 100 V, I <sub>D</sub> = 3.7 A <sup>b</sup>	5.6	-	-	S
Dynamic	<u> </u>		_	L			
Input Capacitance	C <sub>iss</sub>		V <sub>GS</sub> = 0 V,	-	3100	-	
Output Capacitance	C <sub>oss</sub>	1	$V_{GS} = 0 \text{ V},$ $V_{DS} = 25 \text{ V},$	-	800	-	рF
Reverse Transfer Capacitance	C <sub>rss</sub>	f = 1	.0 MHz, see fig. 5	-	490	-	
Total Gate Charge	Qg			-	-	200	
Gate-Source Charge	Q <sub>gs</sub>	V <sub>GS</sub> = 10 V	$I_D = 3.8 \text{ A}, V_{DS} = 400 \text{ V},$ see fig. 6 and 13 <sup>b</sup>	-	-	24	nC
Gate-Drain Charge	$Q_{gd}$		ood fig. o drid To	-	-	110	
Turn-On Delay Time	$t_{d(on)}$			-	19	-	
Rise Time	t <sub>r</sub>	V <sub>DD</sub> =	$= 400 \text{ V}, I_D = 3.8 \text{ A},$	-	38	-	ns
Turn-Off Delay Time	$t_{d(off)}$	R <sub>g</sub> =	= 6.2 $\Omega$ , R <sub>D</sub> = 52 $\Omega$ see fig. 10 <sup>b</sup>	-	120	-	""
Fall Time	t <sub>f</sub>			-	39	-	
Internal Drain Inductance	$L_D$	6 mm (0.25")	Between lead, 6 mm (0.25") from package and center of die contact		5.0	-	ml l
Internal Source Inductance	L <sub>S</sub>				13	-	nH
Drain-Source Body Diode Characteristic	s					•	
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET sym showing the	bol	-	-	5.0	_
Pulsed Diode Forward Current <sup>a</sup>	I <sub>SM</sub>	integral revers p - n junction		-	-	21	A
Body Diode Voltage	V <sub>SD</sub>	T <sub>J</sub> = 25 °C	$I_{S} = 3.8 \text{ A}, V_{GS} = 0 \text{ V}^{b}$	-	-	1.8	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>	T <sub>1</sub> =	25 °C, I <sub>F</sub> = 3.8 A,	-	650	980	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	ď	25 °C, I <sub>F</sub> = 3.8 A, /dt = 100 A/μs <sup>b</sup>	-	3.8	5.7	μC
Forward Turn-On Time	t <sub>on</sub>	Intrinsic tu	rn-on time is negligible (turn	on is dor	minated b	by L <sub>S</sub> and	L <sub>D</sub> )

#### Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Pulse width  $\leq$  300 µs; duty cycle  $\leq$  2 %.



#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

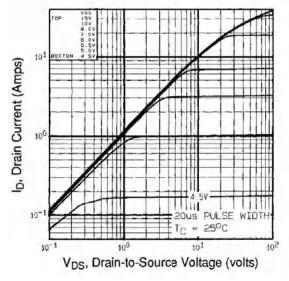


Fig. 1 - Typical Output Characteristics, T<sub>C</sub> = 25 °C

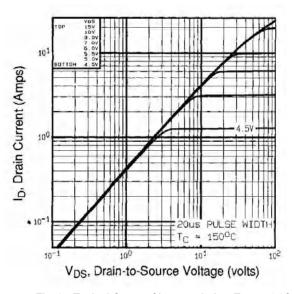


Fig. 2 - Typical Output Characteristics,  $T_C$  = 150 °C

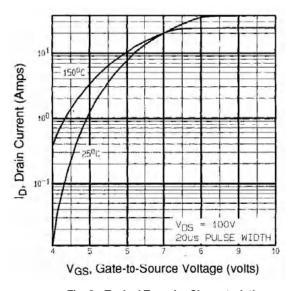


Fig. 3 - Typical Transfer Characteristics

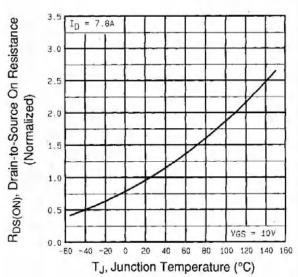


Fig. 4 - Normalized On-Resistance vs. Temperature



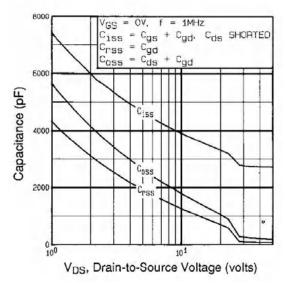


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

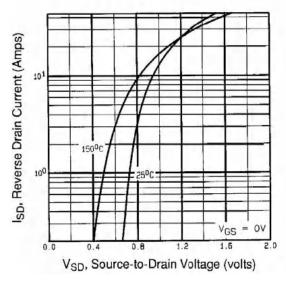


Fig. 7 - Typical Source-Drain Diode Forward Voltage

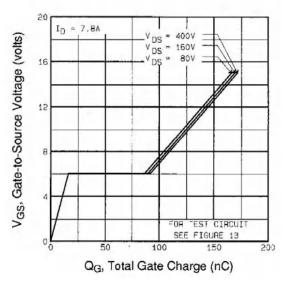


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

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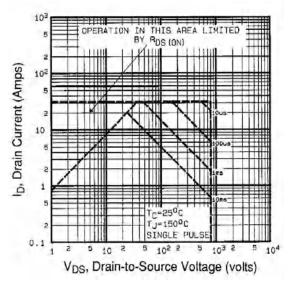


Fig. 8 - Maximum Safe Operating Area



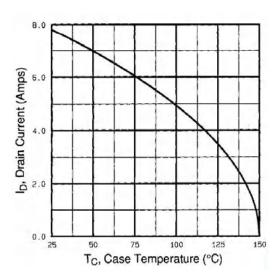


Fig. 9 - Maximum Drain Current vs. Case Temperature

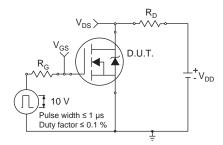


Fig. 10a - Switching Time Test Circuit

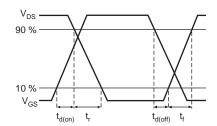


Fig. 10b - Switching Time Waveforms

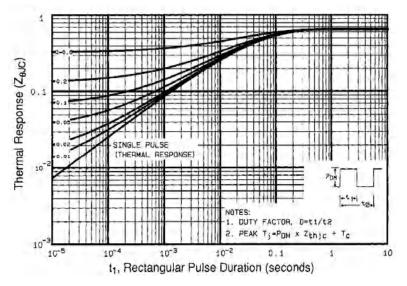


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



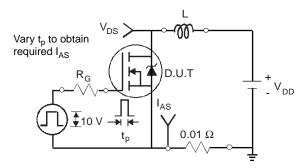


Fig. 12a - Unclamped Inductive Test Circuit

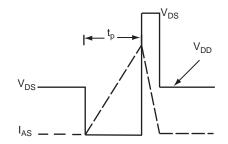


Fig. 12b - Unclamped Inductive Waveforms

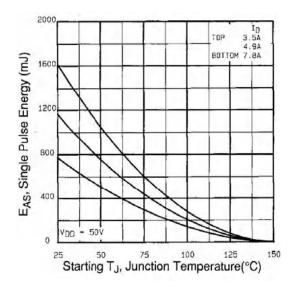


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

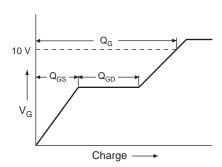


Fig. 13a - Basic Gate Charge Waveform

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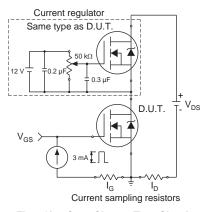
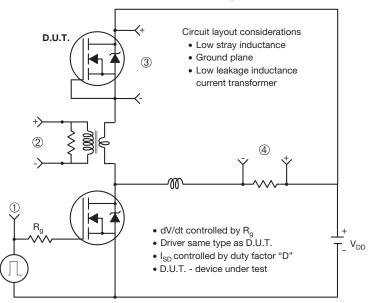


Fig. 13b - Gate Charge Test Circuit



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#### Peak Diode Recovery dV/dt Test Circuit



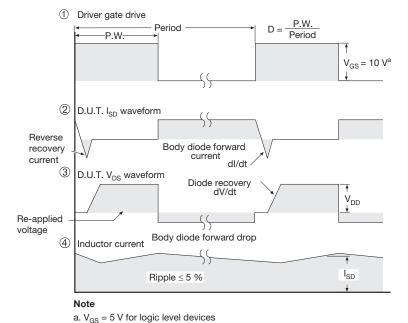
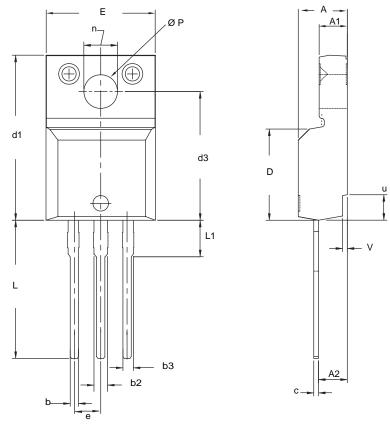


Fig. 14 - For N-Channel



### **TO-220 FULLPAK (HIGH VOLTAGE)**



MAX. 4.830 2.830 2.850 0.890 1.400 1.400 0.629 9.800	MIN. 0.180 0.101 0.099 0.024 0.048 0.048 0.017 0.341	MAX. 0.190 0.111 0.112 0.035 0.055 0.055 0.025
2.830 2.850 0.890 1.400 1.400 0.629 9.800	0.101 0.099 0.024 0.048 0.048 0.017	0.111 0.112 0.035 0.055 0.055
2.850 0.890 1.400 1.400 0.629 9.800	0.099 0.024 0.048 0.048 0.017	0.112 0.035 0.055 0.055
0.890 1.400 1.400 0.629 9.800	0.024 0.048 0.048 0.017	0.035 0.055 0.055
1.400 1.400 0.629 9.800	0.048 0.048 0.017	0.055 0.055
1.400 0.629 9.800	0.048 0.017	0.055
0.629 9.800	0.017	
9.800		0.025
	0.244	0.020
40.400	0.341	0.386
16.120	0.622	0.635
12.920	0.484	0.509
10.630	0.408	0.419
2.54 BSC	0.100	BSC
13.730	0.520	0.541
3.500	0.122	0.138
6.150	0.238	0.242
3.450	0.120	0.136
2.500	0.094	0.098
0.500	0.016	0.020
	6.150 3.450 2.500	6.150     0.238       3.450     0.120       2.500     0.094

#### **Notes**

- To be used only for process drawing.
   These dimensions apply to all TO-220, FULLPAK leadframe versions 3 leads.
   All critical dimensions should C meet C<sub>pk</sub> > 1.33.
   All dimensions include burrs and plating thickness.
   No chipping or package damage.



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